	Phoenix V|tome|x L300	Phoenix V|tome|x L450	Phoenix Power|scan HE
Primary X-ray source	300 kV / 500 W microfocus	450 kV / 1500 W minifocus	9 MeV linear accelerator
Optional additional X-ray source for higher resolution	180 kV / 20 W nanofocus	300 kV / 500 W microfocus	450 kV / 1500 W minifocus
Max. CT scanning volume (Ø x height) *	900 mm Ø x 600 mm	1300 mm Ø x 1250 mm	1920 mm Ø x 2000 mm
Max. sample weight *	50 kg	100 kg	1000 kg
Min. focal spot (F) / Max. detail detectability (D)	D <1 µm with 300 kV tube, optional 200 nm with 180 kV tube	F 1 mm @ 1500 W, optional D <1 µm with 300 kV tube	F <1.5mm @ 20 Gy/min/m, optional 1 mm @ 1500 W with minifocus tube
Geometric magnification	1.25x - 238x (2D)/187x (3D)	1.25x - 400x (2D)/242x (3D)	4.5x
Granite based Manipulation	7 axes	7 axes	11 axes
Focus detector distance (FDD)	400 - 1500 mm	600 - 2500 mm (microfocus) 990 - 2810 mm (minifocus)	5300 mm
Cabinet dimensions (W x H x D) in mm)	4100 x 2600 x 2800 mm (without console & switch cabinet)	6400 x 3900 x 4300 mm (without console & switch cabinet)	Manipulator 8000 x 4300 x 3800 mm (without bunker, console & switch cabinet)
Weight approx. without / with cabinet *	8.5 t / 22.7 t	15 t / 63 t	~48 t / bunker required
Flat panel detector (DDA)	16" Dynamic 41|100 100µm for high contrast high resolution or 16" Dynamic 41|200 200 µm for high contrast high througput		High radiation proof DXR S200 HE 200 µm pitch detector
Optional line detector (LDA)	614 mm length at 0.4 mm pixel pitch, 2x detector shift		820 mm length at 0.4 mm pixel pitch, 2x shift
Flat panel detector shift	2x	3x	4x
Offset|CT	Scan bigger parts or the same size parts with higher resolution		
Optional Orbit|scan	Define a virtual scan rotation axis for ease of scan adjustment and flexible ROI scans.		–
Helix|CT	Scan long samples with improved image quality		
High-flux|target	Faster microCT Scans or doubled scan resolution		-
Multi|BHC	Beam-hardening correction in multi-material scans		
Scatter|correct	Patented scatter radiation artifact reduction		
ASC|filter	Adaptive filter optimization		-
2D inspection capability	Additional tilt/rotate axes + Flash!™ image optimization software		-
Opt. Metrology|edition	SD ≤ (6.8 ± L/100 mm) µm	SD ≤ (6.8 ± L/100 mm) µm	-

* Values in table represent the standard configuration. Additional values are available on request.